



For use with a fixtureless board tester

# Probe Catalog

Automatic Testing Equipment



 1172-58	 1172-59	 1172-59	 1172-61	 1172-62
SHOCK-ABSORBING SINGLE NEEDLE PROBE(SK)	SHOCK-ABSORBING SINGLE NEEDLE PROBE(WC)	SHOCK-ABSORBING SINGLE NEEDLE PROBE(WC SR10)	LINK PROBE	DOUBLE LINK PROBE
 1172-63	 1172-64	 1172-65	 1172-66	 1172-67
DOUBLE LINK PROBE(HP)	LINK PROBE WITH BLADE	DOUBLE LINK PROBE WITH BLADE	LINK PROBE	DOUBLE LINK PROBE
 1172-69	 1172-70	 1172-71	 1172-72	 1172-73
DOUBLE LINK PROBE WITH BLADE	SHOCK-ABSORBING SINGLE NEEDLE PROBE(SK)	SHOCK-ABSORBING SINGLE NEEDLE PROBE(WC)	SHOCK-ABSORBING TRIANGULAR PYRAMID PROBE(SK)	PROBE FOR CALIBRATION <small>(For use with measurement section calibration unit)</small>
 1172-68	 1172-74	 1172-75	 1172-76	 1172-77
LINK PROBE WITH BLADE	PROBE FOR CALIBRATION <small>(For use with measurement section calibration unit)</small>	SHOCK-ABSORBING SINGLE NEEDLE PROBE (HP)	SHOCK-ABSORBING SINGLE NEEDLE PROBE (HP SR10)	SHOCK-ABSORBING SINGLE NEEDLE PROBE (WC SR10)
 1172-80	 1172-81	 1172-82	 1172-83	 1164-03
PROBE	LINK PROBE	LINK PROBE	DOUBLE LINK PROBE(HP)	PROBE ATTACHMENT



ISO14001  
JQA-E-90091



<http://www.hioki.co.jp/>

HIOKI company overview, new products, environmental considerations and other information are available on our website.

Whether with today's increasingly advanced high-density IC packages or in bare board factories, HIOKI's board testers play a vital role. A variety of probes are available for use with fixtureless type board testers. For optimum utility, select the probe that is best suited for your application.